

## Table of contents

- **Digital Testing and the Need for Testable Design**
- **Principles of Testable Design**
- **Pseudorandom Sequence Generators**
- **Test Response Compression Techniques**
- **Shift-Register Polynomial Division**
- **Special-Purpose Shift-Register Circuits**
- **Random Pattern Built-In Test**
- **Built-In Test Structures**
- **Limitations and Other Concerns of Random Pattern Testing**
- **Test System Requirements for Built-In Test**
- **Appendix**
- **References**
- **Index**